Session 12
Reiming and Sequential ATPG

Chair: Sandip Kundu
Organizer: S. Kundu

Sequential automatic test pattern generation is a challenging problem. The papers in this session investigate the effect of retiming on testability, combination of ad hoc and deterministic approaches for faster test generation and synthesis techniques for higher fault coverage.

12.1 On Test Set Preservation of Retimed Circuits*
Aiman El-Maleh, Thomas Marchok, Janusz Rajski, Wojciech Maly

12.2 Combining Deterministic and Genetic Approaches for Sequential Circuit Test Generation
Elizabeth M. Rudnick, Janak H. Patel

12.3 Partial Scan with Pre-selected Scan Signals
Peichen Pan, C. L. Liu

*Best Paper Award candidate